


<b>Search Notes</b>  	<b>Application/Control No.</b>  10585408	<b>Applicant(s)/Patent Under Reexamination</b>  NOZAWA ET AL.
	<b>Examiner</b>  Keath T Chen	<b>Art Unit</b>  1792

SEARCHED			
Class	Subclass	Date	Examiner
118	723R,715	7/2/2008	Keath Chen

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search	6/30/2008	Keath Chen
IDS report search	6/21/2008	Keath Chen
Report to Ram Kackar	7/1/2008	Keath Chen
Text search (See EAST search note)	7/2/2008	Keath Chen
Update search (See EAST search note)	12/18/2008	Keath Chen
Report to Ram Kackar	12/17/2008	Keath Chen
Update Search (See EAST search note)	7/2/2009	Keath Chen
Report to Ram Kackar	7/6/2009	Keath Chen

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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